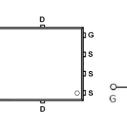


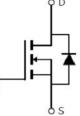
SSF3108J7U

Main Product Characteristics:

V _{DSS}	30V		
R _{DS} (on)	6.7mΩ (typ.)		
I _D	25A		







PQFN 5x6-8L

Pin Assignments

Schematic Diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute Max Rating:

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V ①	25	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V ①	17	А
I _{DM}	Pulsed Drain Current 2	50	
$P_{D} @T_{C} = 25^{\circ}C$	Power Dissipation ③	30	W
V _{DS}	Drain-Source Voltage	30	V
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy @ L=0.5mH	68	mJ
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to + 150	°C



Thermal Resistance

Symbol	Characteristics	Тур.	Max.	Units
R _{θJC}	Junction-to-case③		4.2	°C/W

Electrical Characteristics $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	30	—	—	V	$V_{GS} = 0V, I_D = 250 \mu A$
D	Statia Drain ta Cauraa an raaintanaa	_	6.7	10	mΩ	V_{GS} =10V, I_D = 15A
R _{DS(on)}	Static Drain-to-Source on-resistance		12	16		V _{GS} =4.5V,I _D = 10A
$V_{GS(th)}$	Gate threshold voltage	1.0	_	2.5	V	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$
I _{DSS}	Drain-to-Source leakage current	_	_	1	μA	$V_{DS} = 30V, V_{GS} = 0V$
	Cata to Source forward lookage		—	100		V _{GS} =20V
I _{GSS}	Gate-to-Source forward leakage		—	-100	nA	V _{GS} = -20V
Qg	Total gate charge		12	—		I _D = 15A,
Q_{gs}	Gate-to-Source charge	_	3	—	nC	V _{DS} =15V,
Q_{gd}	Gate-to-Drain("Miller") charge		4	—		$V_{GS} = 10V$
t _{d(on)}	Turn-on delay time		8.3	—		V _{GS} =10V,
t _r	Rise time		19.3	—		V _{DS} =22V,
t _{d(off)}	Turn-Off delay time		23.1	—	ns	$R_{GEN}=2.2\Omega$,
t _f	Fall time		5.5	—		I _D =10A
C _{iss}	Input capacitance	_	960	—		$V_{GS} = 0V$
C _{oss}	Output capacitance	_	144	—	pF	V _{DS} = 25V
C _{rss}	Reverse transfer capacitance	—	120	—		f = 1MHz

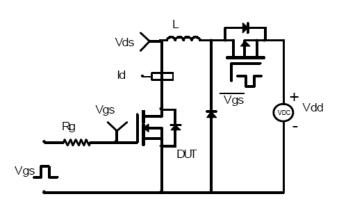
Source-Drain Ratings and Characteristics

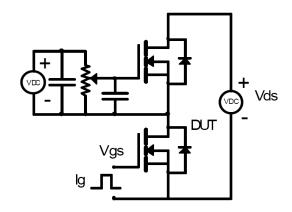
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current		_	25	А	MOSFET symbol
	(Body Diode)	—				showing the
I _{SM}	Pulsed Source Current	_	_	50	А	integral reverse
	(Body Diode)					p-n junction diode.
V _{SD}	Diode Forward Voltage	—	_	1.2	V	I _S =15A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	—	12	_	ns	$T_J = 25^{\circ}C, I_F = 10A,$
Q _{rr}	Reverse Recovery Charge	_	4		nC	di/dt = 100A/µs



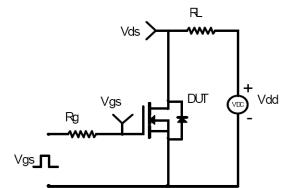
Test Circuits and Waveforms

EAS Test Circuit



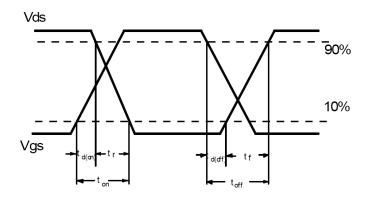


Switching Time Test Circuit



Switching Waveforms

Gate Charge Test Circuit



Notes:

- ①Continuous current tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2 Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.



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Typical Electrical and Thermal Characteristics

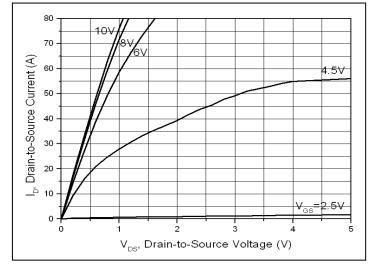


Figure 1. Typical Output Characteristics

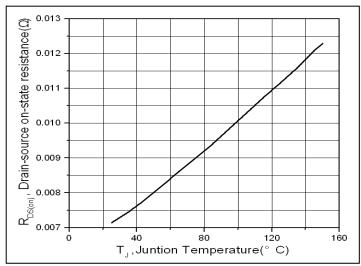


Figure 3. Normalized On-Resistance vs. Junction Temperature

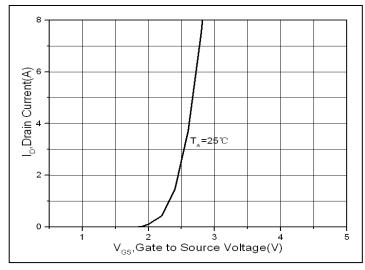
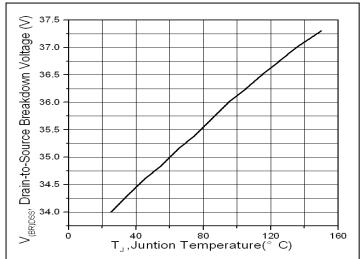
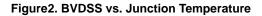


Figure 5. Transfer Characteristics





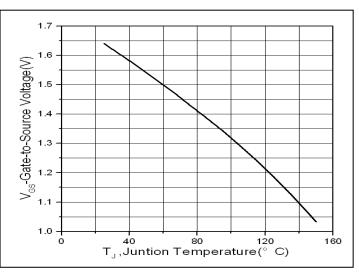
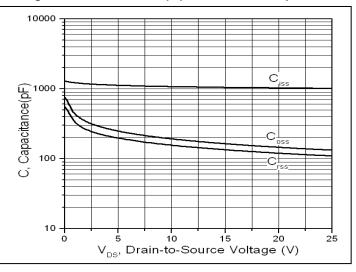


Figure 4. Normalized V_{GS}(th) vs. Junction Temperature







SSF3108J7U

Typical Electrical and Thermal Characteristics

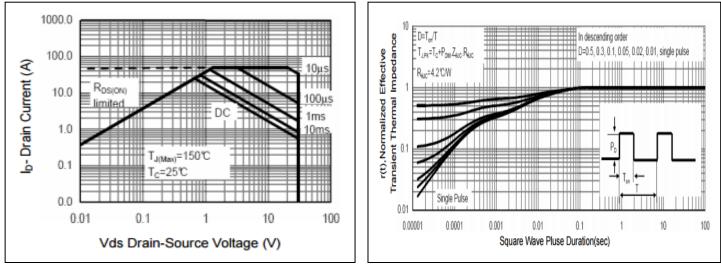


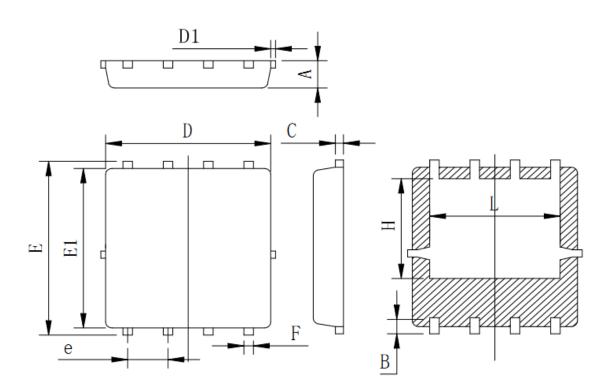
Figure 7. Safe Operation Area

Figure 8. Transient Thermal Impedance



Mechanical Data

PDFN5*6 Package Outline (Unit:mm)



Symbol	Min	Тур	Max
А	0.90	0.95	1.00
В	0.48	0.58	0.68
С	0.20	0.254	0.30
D	5.00	5.20	5.40
Dl			0.15
E	5.90	6.05	6.20
El	5.40	5.55	5.70
e	1.22	1.27	1.32
F	0.25	0.30	0.35
Н	3.27	3.47	3.67
L	3.80	4.00	4.20



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